

**Search Notes**

Application/Control No.

10/752,094

Examiner

Hau V. Phan

Applicant(s)/Patent under  
Reexamination

FRAZIER ET AL.

Art Unit

3618

**SEARCHED**

Class	Subclass	Date	Examiner
280	11.221 11.3 11.27	1/24/2006	HP
	11.223		
	11.224		
	1.225		
	11.227		
	11.231		
	11.233		
	11.28		
	11.19		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR